

Notice of References Cited

Application/Continuation No.

09/915,608

Applicant(s)/Patent Under
Reexamination
FENTON ET AL.

Examiner

Uyen T. Le

Art Unit

2171

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,567,800	05-2003	Barrera et al.	707/3
	B	US-2002/0032019	03-2002	Marks et al.	455/414
	C	US-6,128,663	10-2000	Thomas, C. Douglass	709/228
	D	US-2003/0066085	04-2003	Boyer et al.	725/104
	E	US-2002/0116518	08-2002	Silen et al.	709/231
	F	US-6,317,784	11-2001	Mackintosh et al.	709/219
*	G	US-5,483,651	01-1996	Adams et al.	707/1
*	H	US-2002/0019768	02-2002	Fredrickson et al.	705/14
*	I	US-2002/0092019	07-2002	Marcus, Dwight	725/37
*	J	US-2002/0053078	05-2002	Holtz et al.	725/14
*	K	US-2002/0094189	07-2002	Navab et al.	386/4
*	L	US-2002/0180774	12-2002	Errico et al.	345/721
*	M	US-2002/0049704	04-2002	Vanderveldt et al.	707/1

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	60266091			
	V				
	W				
	X				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Re